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FOREIGN PATENT DOCUMENTS

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<i>[Signature]</i>	JP 2003-233931		08/2003	Kojima et al.		

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Atty. Dkt. No.	M#	Client Ref.
	008312-0306969	T7KO-03S1080

Applicant: ASHIDA et al.
Appln. No.: 10/717,963
Filing Date: November 21, 2003
Examiner: Unassigned <i>[Signature]</i> Group Art Unit: 2655 1756

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Date: April 29, 2005

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U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
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FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YY YY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
OR	JP 2001-167475 A	06/2001	Japan	NONAKA et al.		x		
PR	JP 2001-126308 A	05/2001	Japan	ARAI et al.		x		
QR	JP 11-339314 A	12/1999	Japan	NAGINO et al.		x		
RR	JP 03-125343 A	05/1991	Japan	SUZUKI et al.		x		
SR	JP 10-116441 A	05/1998	Japan	ROSEN et al.		x		
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VR	JP 2002-298433 A	10/2002	Japan	YUZUSU et al.		x		
WR						x		
XR								

OTHER (including in this order: Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

YR	Japanese Office Action dated March 29, 2005 for Appln. No. 2002-339437
ZR	Japanese Office Action dated March 29, 2005 for Appln. No. 2002-342896
AAR	
BBR	

Examiner <i>[Signature]</i>	Date Considered: <i>4/21/06</i>
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INFORMATION DISCLOSURE STATEMENT
 BY APPLICANT

Applicant: SUMIO ASHIDA et al.

Appln. No.: UNASSIGNED

Filing Date: November 21, 2003

Examiner: UNKNOWN Group Art Unit: UNKNOWN

Date: November 21, 2003

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U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AR						
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ER						
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HR						
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	Document Number	Date MM/YYYY	Country	Inventor Name		Enclosed	No	Enclose	No
UR	2003-67974	03/2003	Japan	Inao et al.		X			X
UR	2000-322770	11/2000	Japan	Osada et al.		X			X
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TR	T. Inase et al., "Investigation of Protective Layer for High Transfer Rate Phase Change Optical Disk," Tokyo Research Lab., Tosoh Corp., pages 37-42
UR	Mayumi Uno et al., "Acceleration of crystallization process by nitride interface layer," Optical Disk Systems Development Center, Matsushita Electric Industrial Co., Ltd., pages 85-90
VR	Rie Kojima et al., "Ge-Sn-Sb-Te Phase-change Recording Material Having High Crystallization Speed," Optical Disk Systems Development Center, Matsushita Electric Industrial Co., Ltd., pages 36-41
WR	Michiaki Shinotsuka et al., "High-speed Blue-laser Recording on the Double-decker Phase Change Disk with High-Reliability," Research and Development Group, Ricoh Company, Ltd., IEEE 2002, pages 234-236
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